

Search Notes

Application/Control No.

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Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

MIYAO ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
Search	Updated	1/01	hmk

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR